Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/564,034	MIYAGAWA ET AL.
Examiner	Art Unit

3618

Hau V. Phan

SEARCHED					
Class	Subclass	Date	Examiner		
180	291 274 297 784	6/22/2007	HP		
	300				
	312				
248	605	6/22/2007	HP		
	562				
	634				
267	140.3	6/22/2007	HP		
	141.2				
296	187.09	6/22/2007	HP		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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